

**Notice of References Cited**

Application/Control No.

10/065,225

Applicant(s)/Patent Under  
Reexamination  
BECK ET AL.

Examiner

John P. Sheehan

Art Unit

1742

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	N	61-73853	04-1986	Japan	Abeyama et al.	420/448
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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